

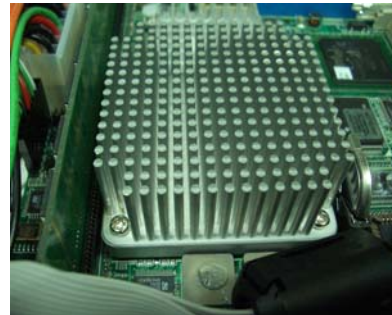
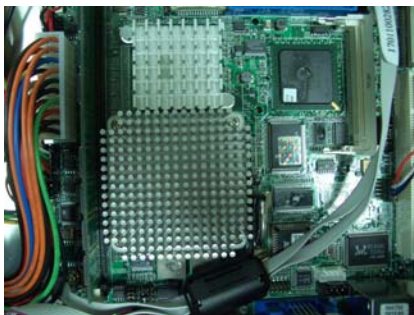
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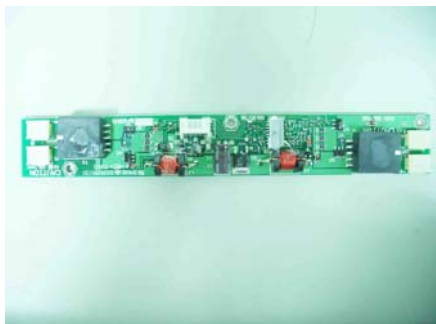
Test Configuration:

Num	Item	Spec
1.	Operator Panel:	AOP-8150WT-A3
	1.LCD	15" CPT TFT-LCD CLAA150XP 03
	2.AC ADAPTER	SINPRO MPU100-108 (I/P: 100~240VAC O/P: 24V/4.16A)
	3.DC/DC POWER SUPPLY	EPD-146 Rev : C
	4. Inverter	HWA YOUN QF83v3.21
2.	CPU Board:	EMB-852T Rev: A1.1
	1. Bios Ver.	AOP-8150WT-AX BIOS Rev:1.3
	2.CPU	Intel Celeron M Processor 600MHz
	3.Memory	DSL 256MB SAMSUNG K4H560838H-UCB3 (DDR333)
	4. HDD	FUJITSU MHW2040AT / 40GB
	5.Test Software	Windows XP / Run PassMark Burn In Test 5.1 Pro

CPU Heat Sink



Inverter



Temperature cycle test

Test Date: 01-16~18-2008

Test Product: AOP-8150WT-A3

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

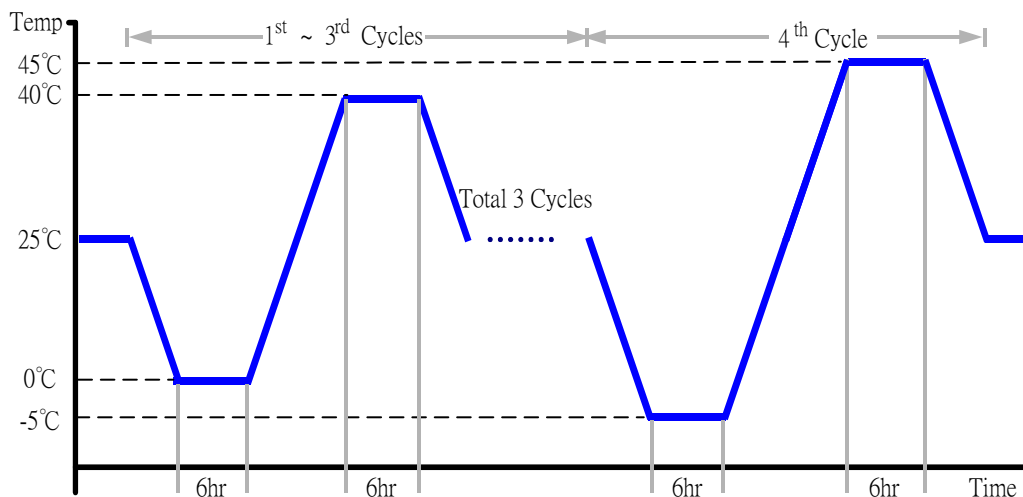
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/16/07
Serial Number: 1241

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/13/07
Serial Number: 12A323190

Test Condition:

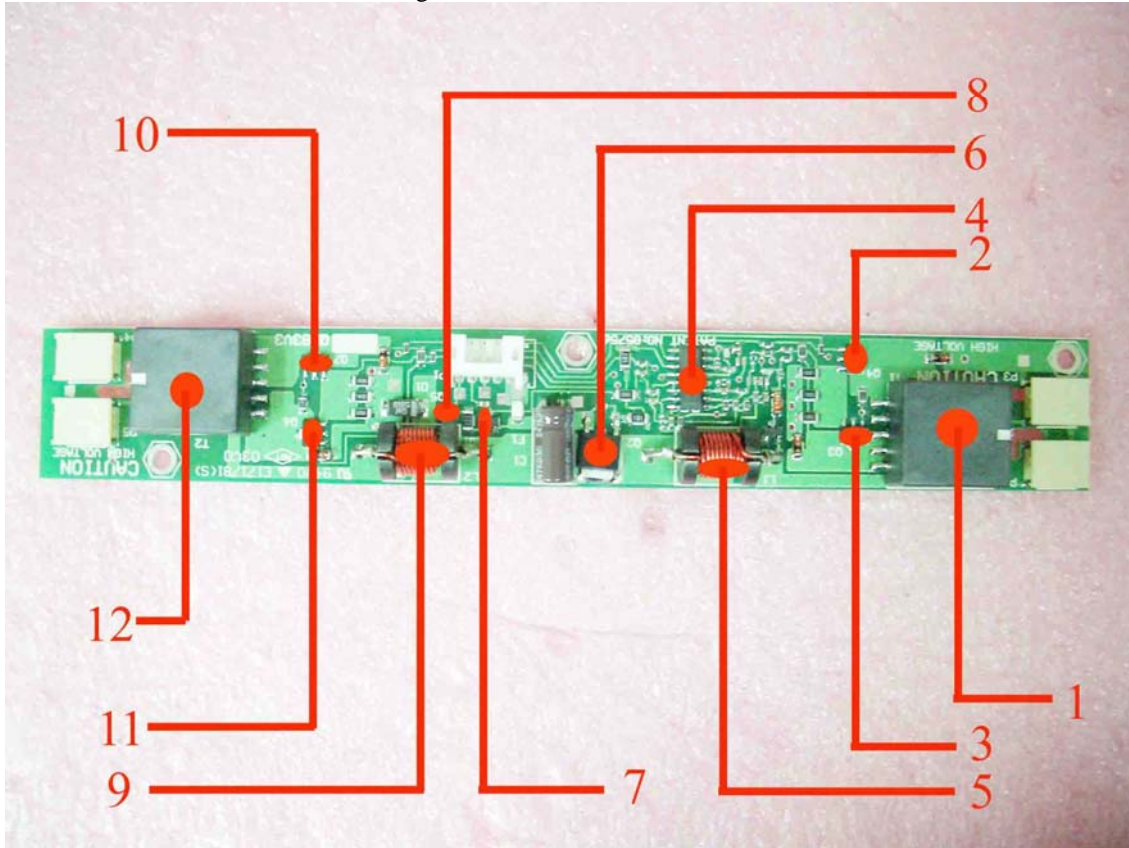
1. Test Low Temperature: 0°C (1~3 cycles)
-5°C (4th cycle)
2. Test High Temperature: 40°C (1~3 cycles)
45°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



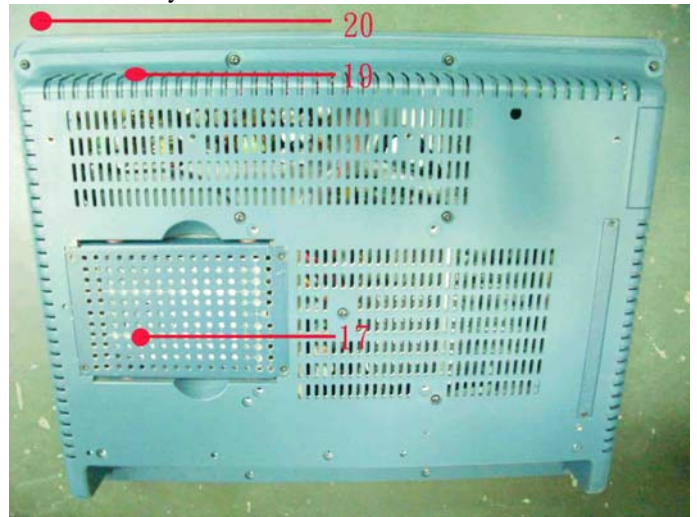
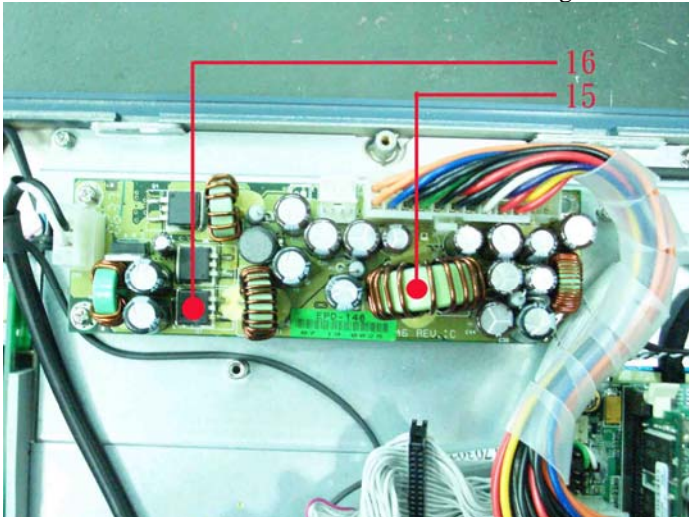
Temperature cycle test

Terminal Recorder:

Measuring Accelerometer Position - Inverter



Measuring Accelerometer Position - System



Temperature cycle test

Thermal profile data:

AOP-8150WT-A3

Point	Temp. Stage(°C)	Spec	40	25	0
Inverter					
1. Inverter - T1		200	82.3	67.3	42.3
2. Inverter - Q4		150	79.9	64.9	39.9
3. Inverter - Q3		150	82.6	67.6	42.6
4. Inverter - IC1		85	77.9	62.9	37.9
5. Inverter - L1		150	88.9	73.9	48.9
6. Inverter - Q2		150	78.9	63.9	38.9
7. Inverter - Q1		150	90.6	75.6	50.6
8. Inverter - Q5		150	90.4	75.4	50.4
9. Inverter - L2		150	79.5	64.5	39.5
10. Inverter - Q7		150	92.4	77.4	52.4
11. Inverter - Q6		150	86.7	71.7	46.7
12. Inverter - T2		200	79.7	64.7	39.7
EMB-852T					
1. U24-Chipset.NB82852GM.Intel.RG82852GM		105	70.2	55.2	30.2
2. U23-INTEL CPU.Celeron-M.ULV 600MHz.		100	71.1	56.1	31.1
3. U25-Chipset ICH4.INTEL.FW82801DB		110	64.0	49.0	24.0
4. U13-2A Bus Termination Regulator.Winbond.W83310S-R2		100	72.3	57.3	32.3
5. U54-ACPI Power Controller.Intersil.ISL6506BCB		100	68.1	53.1	28.1
6. U10-N-Channel.30V.10A.13.5mΩ .MOSFET.APEC.AP4410M		125	70.2	55.2	30.2
7. L2- INDUCTOR.3.3uH.20%. VISHAY.IHLP2525CZRZ3R3M01		125	70.0	55.0	30.0
8. U11-Step-Down DC/DC Controller.Anpec.APW7057		100	69.3	54.3	29.3
9. U57-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	58.0	43.0	18.0
10. U22-CLOCK GENERATOR.ICS.ICS952601		115	65.8	50.8	25.8
11. U45-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	56.1	41.1	16.1
12. U44-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	56.7	41.7	16.7
13. TC25-220uF.2V.Panasonic.EEFSX0D221YR		105	67.5	52.5	27.5
14. TC27-150uF.6.3V.Panasonic.ECGUD0J151R		105	66.2	51.2	26.2
15. Power Supply Heat Sink Surface - 1		N/A	93.3	78.3	53.3
16. Power Supply Heat Sink Surface - 2		N/A	70.6	55.6	30.6
17. HDD		55	52.9	37.9	12.9
18. Memory		70	59.2	44.2	19.2
19. Control Box Surface		N/A	56.4	41.4	16.4
20. Chamber Air Temperature		N/A	40.8	25.8	0.8
Any Tm value showed in red words which meaning the value over the Tc + 5 degree C of this device specification					

Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8150WT-A3)

Test Result:

1. No problem was found during the temperature operation cycle test.

Test Date: 01-28~30-2008

Test Product: AOP-8150WT-A3

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/16/07
Serial Number: 1241

Testing Item:

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8150WT-A3)

Test Result:

No problem was found after the high temperature storage test.

Test Date: 01-30-2008~02-01-2008

Test Product: AOP-8150WT-A3

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/16/07
Serial Number: 1241

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8150WT-A3)

Test Result:

No problem was found after the low temperature storage test.

Test Date: 01-25~27-2008

Test Product: AOP-8150WT-A3

Test Site: AAEON QA Internal Lab.

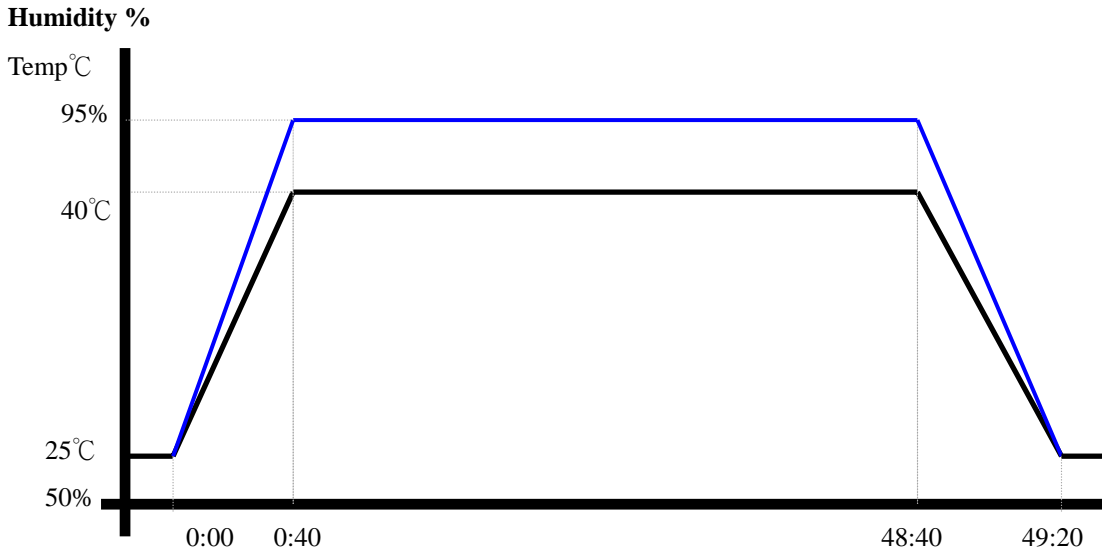
Performed By: Rex Chang

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/16/07
Serial Number: 1241

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AOP-8150WT-A3)

Test Result:
No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 01-23~24-2008

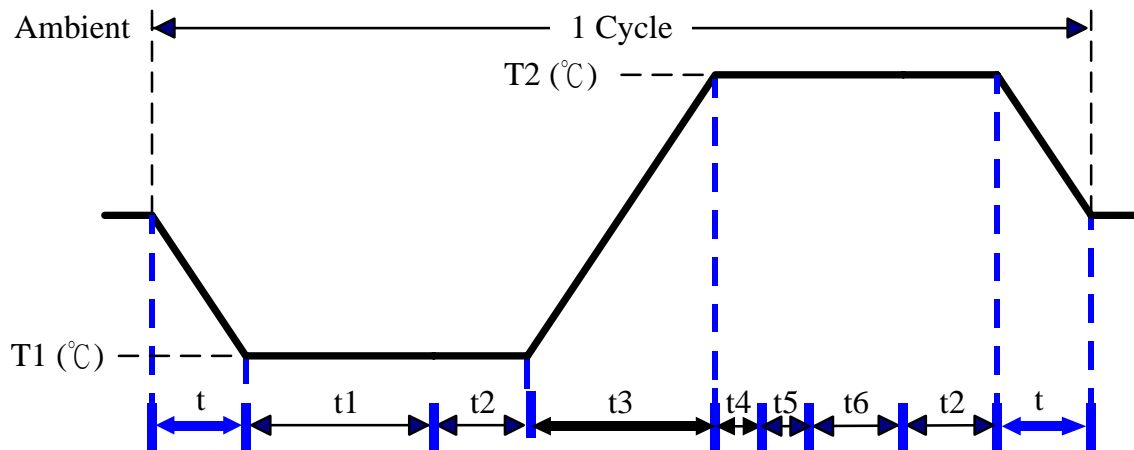
Test Product: AOP-8150WT

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/16/07
Serial Number: 1241

Test Condition:



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope
t , t1, t6: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3, t4: Run PassMark Burn In Test
t5: Win XP Software restart test 3 times
Test Software: Windows XP

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.